

AMTC1 The 1st International Symposium on Advanced Microscopy and Theoretical Calculations



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Call for Poster Papers at AMTC1

Dear colleague,

The 1st International Symposium on Advanced Microscopy and Theoretical Calculations (AMTC1) will be held from June 29 to 30, 2008 at the Nagoya Congress Center, Nagoya, Japan.

This symposium will be held in commemoration of the establishment of the Nanostructures Research Laboratory at the Japan Fine Ceramics Center, and plans are also being made to hold a similar symposium every other year. The purpose of the 2008 symposium is to bring together leading scientists and engineers from all over the world in order to discuss in depth a specific theme related to latest developments in microscopy and in computational techniques used both for nanostructure analysis and for the design of advanced materials. Coverage of topical subjects is confidently expected to lead to future breakthroughs in materials science and engineering, and ultimately to be of benefit to environmental protection and to sustainable development throughout the world. The first symposium will take the form of approximately 25 oral talks by invited speakers. Poster presentations are also planned.

Participants are encouraged to present their recent research at a poster session of the symposium.

Extended abstracts of a length of two pages should be submitted before March 31, 2008.

Chairpersons: T. Hirayama, Y. Ikuhara, I. Tanaka

Poster Session

- **Poster size**
A0 size (Width 84cm Height 120cm)

Symposium Topics

The symposium covers all relevant fields in advanced microscopy and theoretical calculations:

- High Resolution Electron Microscopy (HREM),
- Scanning Transmission Electron Microscopy (STEM),
- Electron Holography,
- Nano-scale spectroscopy with the use of EELS, EDS and XAFS,
- Theoretical Spectroscopy,
- Advanced Techniques in Electron Microscopy,
- Environmental Microscopy,
- Interface and Grain Boundaries,
- Lattice Imperfections,
- First Principles Theory and Modeling,
- Materials Informatics,
- Fundamental Issues in Materials Science,
- Scanning Probe Microscopy.

Abstract preparation

Author should prepare two page of extended abstract which include significant result with pictures and figures.

Please find attached file (sample.doc) as a sample for extended abstract.

Abstract should be converted into one pdf file, ready to print style.

Abstract submission

Please send your abstract (pdf file) via E-mail.

E-mail: amtc1@jecs.org

Abstract acceptance notification

Authors are notified their acceptance of abstract after peer-reviewing of their abstracts. If they do not receive any correspondence by 15th May 2008, please ask the Secretaria of AMTC1 by E-mail.

E-mail: amtc1@jecs.org

Publication of Abstracts

Accepted abstracts will be published as a special issue of a newly launched international journal, AMTC Letters. It is planned to be distributed at the symposium site.

Requests for further information

Sayaka Hotta,
Secretaria of AMTC1
c/o JTB Event & Convention Service
JTB Support Chubu, Inc.
Phone: +81-52-541-2521 Fax: +81-52-541-2520
E-mail: amtc1@jecs.org

Important date

Abstract submission deadline: March 31 2008

Symposium: June 29 to 30, 2008

- [Call for Poster Papers \(PDF\)](#)



[Abstract Submission Format \(sample.doc\)](#)

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